

Search Notes



Application/Control No.

10/735,884

Examiner

LEE NGUYEN

**Applicant(s)/Patent under
Reexamination**

PAIK ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	415 416 435.1	5/27/2005	LN
	566 567		
379	93.23	5/27/2005	LN
	142.06		
	142.17		
348	14.02	5/27/2005	LN
	14.1		
UPDATE	SEARCH	8/1/2006	LN
	ALL ABOVE		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
SEE SEARCH HISTORY		8/1/2006	LN